

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/618,677	WU, HUNG-YI	
Examiner Oanh Duong		Art Unit 2155	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0043420	03-2003	Hamilton et al.	358/474
*	B	US-2004/0172451	09-2004	Biggs et al.	709/206
*	C	US-6,587,129	07-2003	Lavendel et al.	715/776
*	D	US-2003/0043420	03-2003	Hamilton et al.	358/474
*	E	US-2003/0103250	06-2003	Kidokoro et al.	358/524
*	F	US-2003/0177448	09-2003	LEVINE et al.	715/530
*	G	US-2001/0025326	09-2001	Kizaki, Junichiro	710/100
*	H	US-6,964,025	11-2005	Angiulo et al.	715/838
*	I	US-2003/0227553	12-2003	Mattis et al.	348/231.2
*	J	US-2003/0120729	06-2003	Kim et al.	709/203
*	K	US-6,782,426	08-2004	Kuroshima et al.	709/229
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2004120166 A	04-2004	Japan	ENJOJI et al.	
	O	JP 2000137640 A	05-2000	Japan	OSUGA, NORIYUKI	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Q.L.